

## **FDW2502P**

# **Dual P-Channel 2.5V Specified PowerTrench** MOSFET

### **General Description**

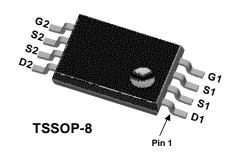
This P-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild's Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V –12V).

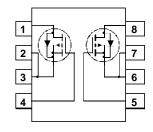
### **Applications**

- Load switch
- Motor drive
- DC/DC conversion
- Power management

#### **Features**

- -4.4 A, -20 V.  $R_{DS(ON)} = 0.035~\Omega~@~V_{GS} = -4.5~V$   $R_{DS(ON)} = 0.057~\Omega~@~V_{GS} = -2.5~V.$
- Extended V<sub>GSS</sub> range (±12V) for battery applications.
- $\bullet$  High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$  .
- Low profile TSSOP-8 package.





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	I Parameter		Ratings	Units
$V_{DSS}$	Drain-Source Voltage		-20	V
$V_{GSS}$	Gate-Source Voltage		±12	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	-4.4	А
	- Pulsed		-30	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	1.0	W
		(Note 1b)	0.6	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	125	°C/W
		(Note 1b)	208	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
2502P FDW2502P		13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	1			I	I
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Referenced to 25°C		-17		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V},  V_{GS} = 0 \text{ V}$			-1	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = -12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	V <sub>GS</sub> = 12 V V <sub>DS</sub> = 0 V			100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-1.0	-1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Referenced to 25°C		3.1		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V},  I_D = -4.4 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -4.4 \text{ ,} T_J = 125^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V},  I_D = -3.3 \text{ A}$		0.028 0.039 0.043	0.035 0.056 0.057	Ω
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, \qquad V_{DS} = -5 \text{ V}$	-30			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -4.4 \text{ A}$		17		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance			1330		pF
Coss	Output Capacitance	$V_{DS} = -10 \text{ V}, \qquad V_{GS} = 0 \text{ V},$ $V_{GS} = 0 \text{ V},$		552		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1.0 MHZ		153		pF
Switchir	g Characteristics (Note 2)				•	•
t <sub>d(on)</sub>	Turn-On Delay Time			12	25	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = -10 \text{ V}, \qquad I_D = -1 \text{ A},$		19	40	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V},  R_{GEN} = 6 \Omega$		60	100	ns
t <sub>f</sub>	Turn-Off Fall Time			37	70	ns
Q <sub>a</sub>	Total Gate Charge			14	20	nC
$Q_{gs}$	Gate-Source Charge	$V_{DS} = -5 \text{ V}, \qquad I_{D} = -4.4 \text{ A},$		3.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	$V_{GS} = -4.5 \text{ V}$		3.9		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
l <sub>s</sub>	Maximum Continuous Drain-Source				-0.83	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_{S} = -0.83 \text{ A (Note 2)}$		-0.7	-1.2	V

### Notes:

<sup>1.</sup> R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.

a) R $_{\theta JA}$  is 125°C/W (steady state) when mounted on a 1 inch² copper pad on FR-4. b) R $_{\theta JA}$  is 208°C/W (steady state) when mounted on a minimum copper pad on FR-4.

<sup>2.</sup> Pulse Test: Pulse Width < 300 µs, Duty Cycle < 2.0%

### **Typical Characteristics**

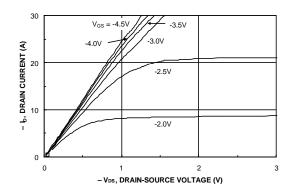


Figure 1. On-Region Characteristics.

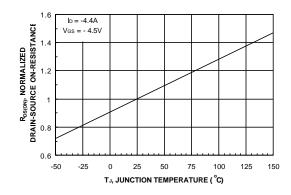


Figure 3. On-Resistance Variation with Temperature.

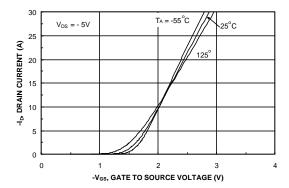


Figure 5. Transfer Characteristics.

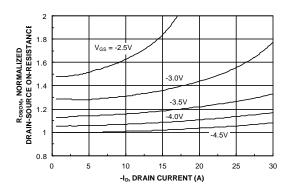


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

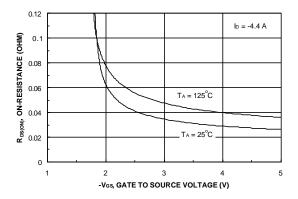


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

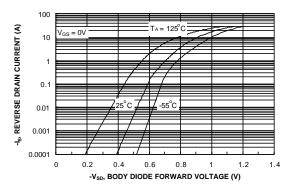
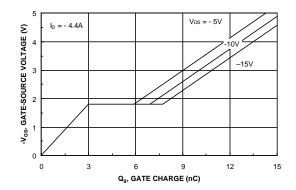


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

### **Typical Characteristics**



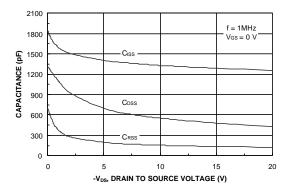
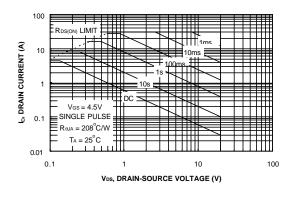


Figure 7. Gate Charge Characteristics.





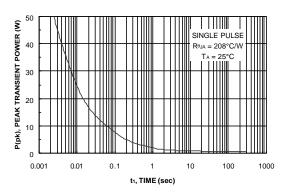


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

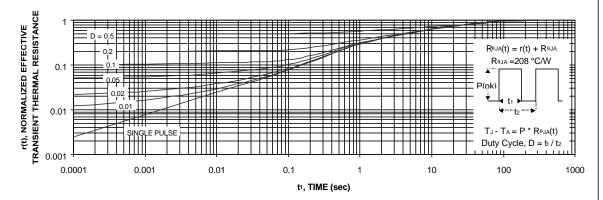


Figure 11. Transient Thermal Response Curve.

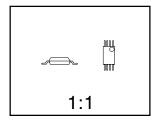
Thermal characterization performed using the conditions described in Note 1. Transient thermal response will change depending on the circuit board design.

### **TSSOP-8 Package Dimensions**

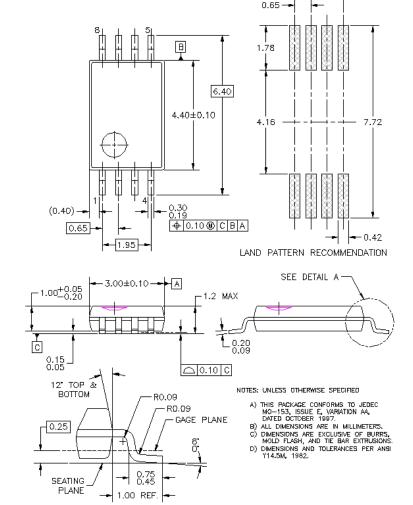


# TSSOP-8 (FS PKG Code S4)





Scale 1:1 on letter size paper
Dimensions shown below are in millimeters
Part Weight per unit (gram): 0.0334



DETAIL A SCALE: 2X

MTCOBREVB

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